

## Transaction Information

Tool ID	ETS445
Tool Status	Disconnected
Location	Dresden, Germany
Wafer Size	300 mm
Fab Section	Test
Tool Available Date	2021-10-04

## General Product Information

Vendor Supplier	CREDESCENCE
Model	SAPPHIRE
Vintage	2008
Serial No	70413
Asset Description	Wafer Tester
Software Version	LTX Credence customized for AMD/ Globalfoundries
CIM	n/a
Process	Wafer Test

## Hardware Configuration (Fab)

System Type	Description	Quantity	Status
Main System	Tester	1	
Handler System	NONE	0	OK
Factory Interface	NONE	0	OK
Options System	Adapter for TEL P12XIn+	1	OK
Others	n/a	0	OK

## Hardware Configuration (Subfab / Auxilliary Units)

Description	Quantity	Status
cold idled LTX CREDESCENCE Sapphire Tester	1	

## Missing/Faulty Parts / Accesories List

Description	Quantity
channel boards and DPS units defect	5

# Tool Pictures

General

Tool Reference



General

Tool Reference





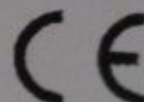


Manufacture Serial

S/N Tool Plate

**credence**

**PRODUCT: SAPPHIRE**  
**MODEL: ENHANCED POWER**  
**S/N: SAPPE-R70413**



**MFG DATE: February 01, 2008**

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## Additional Configuration Files